

MOSFET – P-Channel, QFET

-150 V, -3 A, 1.5 Ω

FDMC2523P

General Description

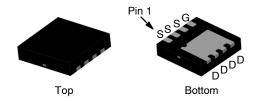
These P-Channel MOSFET enhancement mode power field effect transistors are produced using **onsemi**'s proprietary, planar stripe, DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC-DC converters, and DC motor control.

Features

- Max $R_{DS(on)} = 1.5 \Omega$ at $V_{GS} = -10 \text{ V}$, $I_D = -1.5 \text{ A}$
- Low C_{rss} (Typical 10 pF)
- Fast Switching
- Low Gate Charge (Typical 6.2 nC)
- Improved dv / dt Capability
- This Device is Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

• Active Clamp Switch

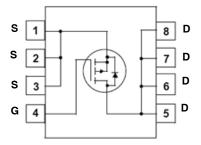


WDFN8 3.3x3.3, 0.65P CASE 511DH

MARKING DIAGRAM

ZXYKK 2523P

Z = Assembly Plant Code
XY = Date Code (Year &Week)
KK = Lot Traceability Code
2523P = Specific Device Code



ORDERING INFORMATION

Device	Package	Shipping [†]
FDMC2523P	WDFN8 (Pb-Free)	3000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

1

MOSFET MAXIMUM RATINGS ($T_A = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter			Ratings	Unit
V _{DS}	Drain to Source Voltage			-150	٧
V_{GS}	Gate to Source Voltage	Gate to Source Voltage			V
I _D	Drain Current	-3	Α		
		Continuous	T _C = 100°C	-1.8	1
		Pulsed	-	-12	1
P_{D}	Power Dissipation (Steady State) T _C = 25°C			42	W
E _{AS}	Single Pulse Avalanche Energy (Note 5)			3.3	mJ
T _J , T _{STG}	Operating and Storage Junction Temperature Range			−55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds			300	°C
dv/dt	Peak Diode Recovery dv/dt	(Note 2)		- 5	V/ns

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	3.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	60	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Symbol	Symbol Parameter Test Conditions Min Typ Max					
		rest conditions	IVIIII	קעי	IVIAA	Unit
OFF CHARA	CTERISTICS					
BV _{DSS}	Drain-to-Source Breakdown Voltage	$I_D = -250 \ \mu A, \ V_{GS} = 0 \ V$	-150	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C	-	-138	-	mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -150 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	-1	μΑ
		V_{DS} = -150 V, V_{GS} = 0 V, T_J = 125 °C	-	-	-10	μΑ
I _{GSS}	Gate-to-Source Leakage Current	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA
ON CHARAC	ON CHARACTERISTICS					
V _{GS(th)}	Gate-to-Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = -250 \mu\text{A}$	-3	-3.8	-5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate-to-Source Threshold Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C	-	6	-	mV/°C
R _{DS(on)}	Static Drain-to-Source	$V_{GS} = -10 \text{ V}, I_D = -1.5 \text{ A}$	-	1.1	1.5	Ω
	On Resistance	$V_{GS} = -10 \text{ V}, I_D = -1.5 \text{ A}, T_J = 125^{\circ}\text{C}$	-	2.0	3.6]
9FS	Forward Transconductance	$V_{DS} = -40 \text{ V}, I_D = -1.5 \text{ A (Note 4)}$	-	1.4	-	S
DYNAMIC C	HARACTERISTICS					
C _{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	200	270	pF
C _{oss}	Output Capacitance		-	60	80	
C _{rss}	Reverse Transfer Capacitance		-	10	15	
R_g	Gate Resistance	f = 1 MHz	0.1	7.5	15	Ω

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
SWITCHING	WITCHING CHARACTERISTICS						
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -75 \text{ V}, I_D = -3 \text{ A}, V_{GS} = -10 \text{ V},$ $R_{GEN} = 25 \Omega \text{ (Note 3, 4)}$	_	15	27	ns	
t _r	Rise Time		-	11	20		
t _{d(off)}	Turn-Off Delay Time		_	19	35		
t _f	Fall Time		_	13	24		
Qg	Total Gate Charge	$V_{GS} = -10 \text{ V}, V_{DD} = -75 \text{ V}, I_D = -3 \text{ A}$	_	6.2	9	nC	
Q _{gs}	Gate-to-Source Charge	(Note 3, 4)	-	1.4	-		
Q_{gd}	Gate-to-Drain "Miller" Charge		_	3.3	-		

DRAIN-SOURCE DIODE CHARACTERISTICS

I _S	Maximum Continuous Drain - Source Diode Forward Current		-	-	-3	Α
I _{SM}	Maximum Pulse Drain - Source Doide Forward Current		-	-	-12	
V _{SD}	Source–to–Drain Diode Forward $V_{GS} = 0 \text{ V}, I_S = -3.0 \text{ A}$ Voltage		ı	-1.8	-5	V
t _{rr}	Reverse Recovery Time	I _F = -3.0 A, di/dt = 100 A/μs (Note 3)	-	93	_	ns
Q _{rr}	Reverse Recovery Charge		_	0.27	_	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

NOTES:

1. R_{0JA} is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta,IC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 60°C/W when mounted on a 1 in² pad of 2 oz copper



b) 135°C/W when mounted on a minimum pad of 2 oz copper

- 2. $I_{SD} \le -3$ A, $dI/dt \le 300$ A/ μ s, $V_{DD} \le B_{VDSS}$, Starting $T_J = 25^{\circ}C$.
 3. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
 4. Essentially independent of operating temperature.

- 5. E_{AS} of 3.3 mJ is based on starting $T_J = 25$ °C, P-ch: L = 3 mH, $I_{AS} = -1.5$ A, $V_{DD} = -150$ V, $V_{GS} = -10$ V.

TYPICAL CHARACTERISTICS

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

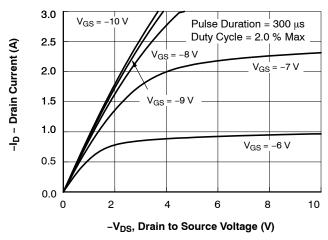


Figure 1. On-Region Characteristics

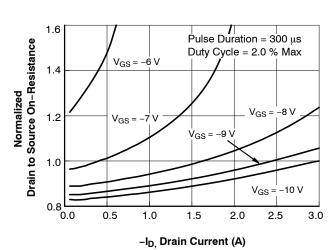


Figure 2. Normalized On–Resistance vs.
Drain Current and Gate Voltage

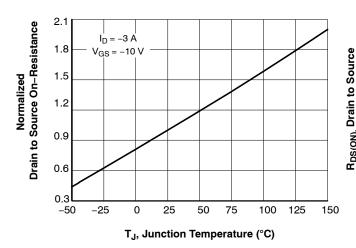


Figure 3. Normalized On-Resistance vs. Junction Temperature

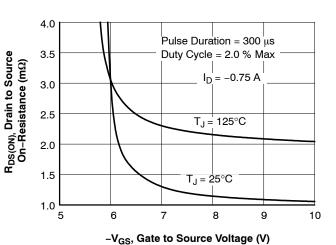


Figure 4. On-Resistance vs.
Gate to Source Voltage

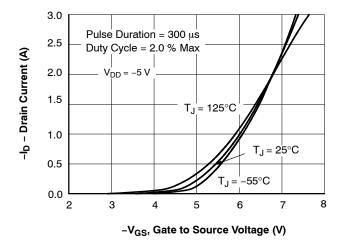


Figure 5. Transfer Characteristics

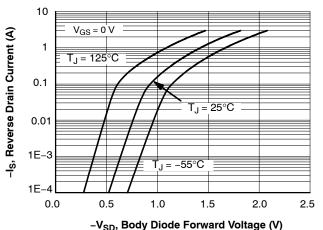


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (continued)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

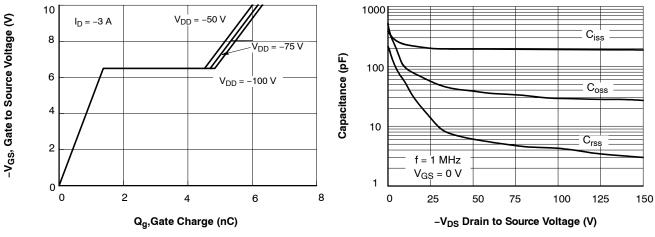
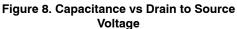


Figure 7. Gate Charge Characteristics



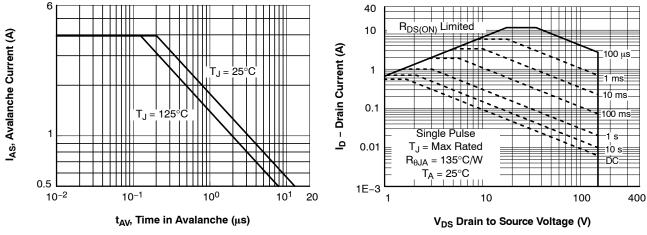


Figure 9. Unclamped Inductive Switching Capability

Figure 10. Forward Bias Safe Operating Area

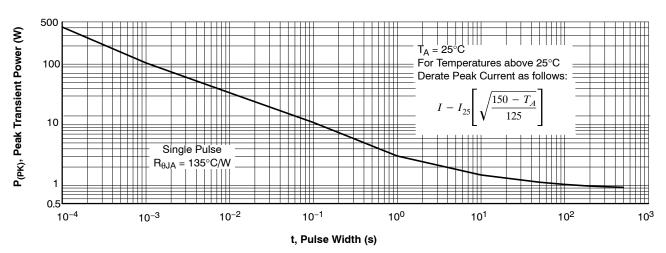


Figure 11. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS (continued)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

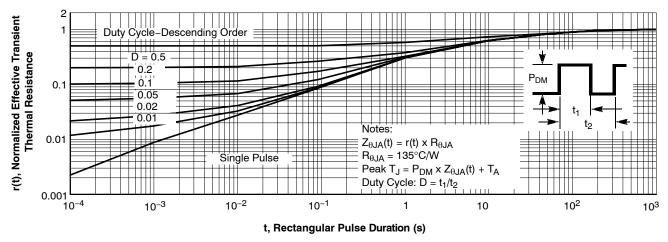
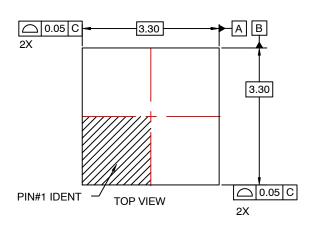
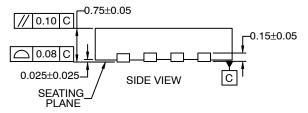


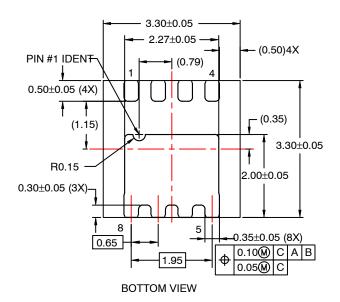
Figure 12. Transient Thermal Response Curve

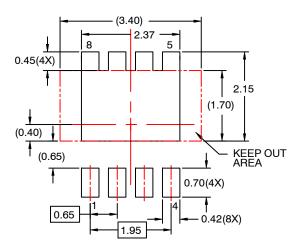
WDFN8 3.3x3.3, 0.65P CASE 511DH ISSUE O

DATE 31 JUL 2016









RECOMMENDED LAND PATTERN

NOTES:

- A. DOES NOT CONFORM TO JEDEC REGISTRATION MO-229
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.

DOCUMENT NUMBER:	98AON13625G	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	WDFN8 3.3X3.3, 0.65P	•	PAGE 1 OF 1	

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, Onsemi, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase

ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:

 $\textbf{Technical Library:} \ \underline{www.onsemi.com/design/resources/technical-documentation}$

onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support

For additional information, please contact your local Sales Representative at

www.onsemi.com/support/sales